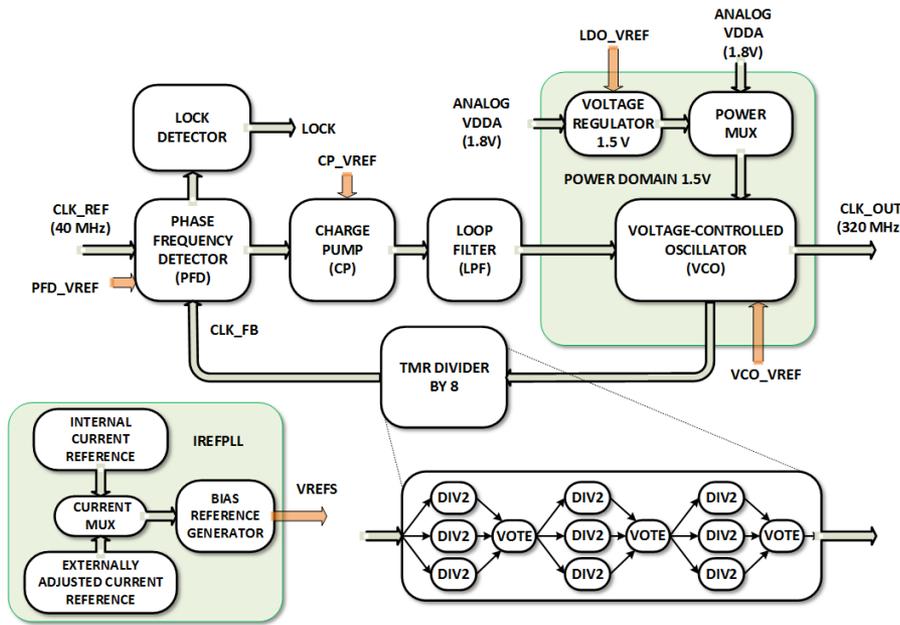


MIMOSIS-2.1 TESTS

PHASE-LOCKED LOOP (PLL)

INTRODUCTION

- A Charge-pump PLL
- Additional features
 - Integrated voltage regulator (LDO) for VCO
 - Integrated Lock detection circuitry
 - Divider with Triple Modular Redundancy (TMR) to protect against single-event upset errors (SEU)
- PLL block generates 320 MHz main clock from 40 MHz input clock signal



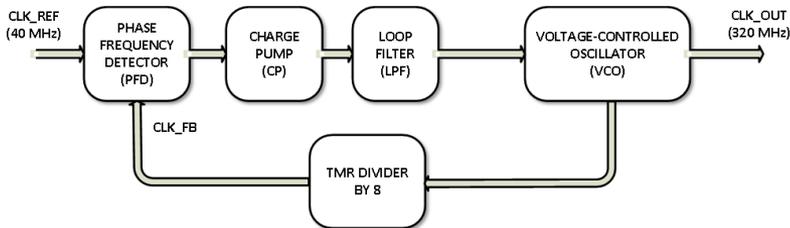
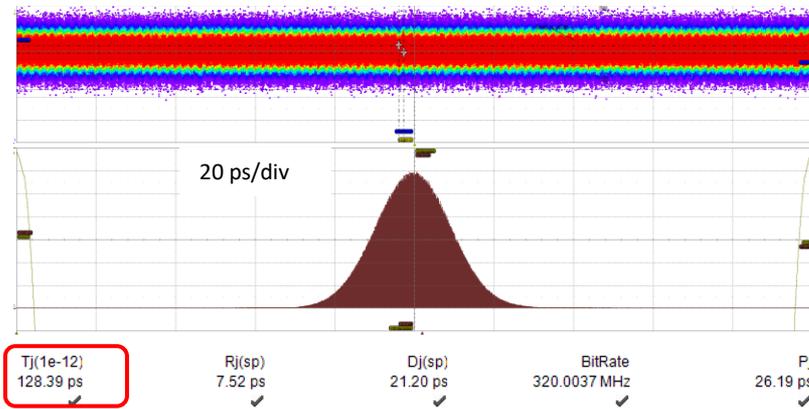
Design Parameters

| Parameter | Value |
|-----------------------------|--|
| Fixed multiplication Factor | 8 |
| Clock input range | 25 MHz to 50 MHz |
| Clock output range | 200 MHz to 400 MHz |
| Locking time | < 15 μ s |
| Duty cycle ratio | 45 \pm 5 % |
| Power supply range | 1.5V to 2.0V |
| Die Area | 360 x 320 μ m ² (0.11 mm ²) |
| Power consumption (Core) | 3.6 mW at 320MHz |

MIMOSIS-2.1 PLL CORE

- PLL core consists of essential building blocks of the PLL:
 - Phase Frequency Detector (PFD), Charge Pump (CP), Loop filter (LPF), Voltage-controller Oscillator (VCO) and Divider
- PLL Core design is operational and fulfils the requirements in low power supply noise conditions
 - voltage regulator LDO disabled, pixel matrix steering and readout not started

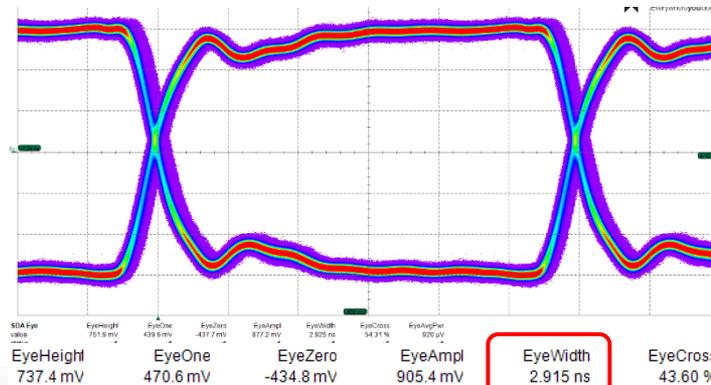
TIE histogram of the CLKPLL and instantaneous clock frequency-tracking plot in persistence mode



Test Results

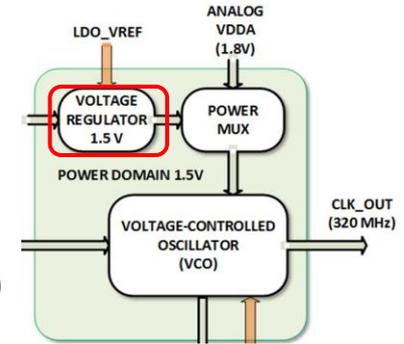
| Parameter | Value |
|---|-----------------------------|
| Clock input range | 25 MHz to 80 MHz |
| Clock output range | 200 MHz to 640 MHz |
| Locking time | 4.6 us |
| Duty cycle ratio | 46% at 320 MHz |
| Total Jitter TJ(BER=1e ⁻¹²) | 128 ps (0.04 UI) at 320 MHz |

Eye diagram DATA[0] LVDS bufferoutput, Data Pattern: ([0xAAAA] x 16), Clock period: 3.125 ns (320 MHz)

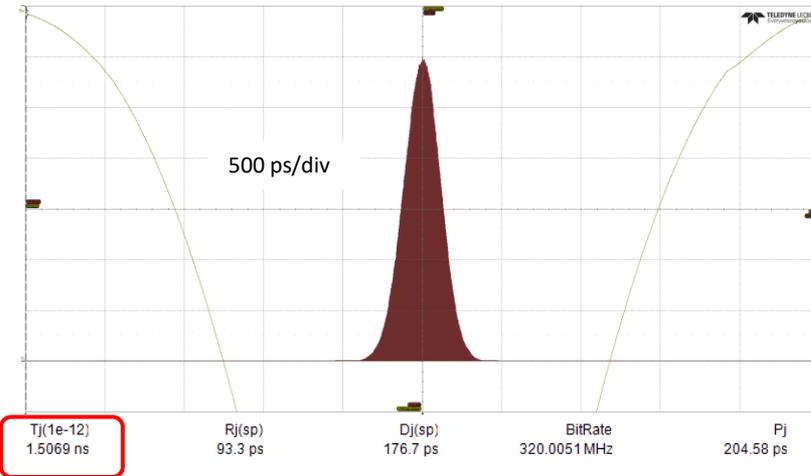


ISSUE 1: INTEGRATED VOLTAGE REGULATOR (LDO)

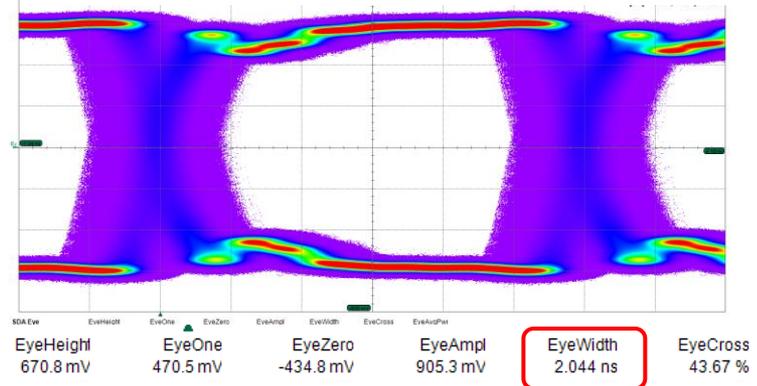
- Main task of the LDO:
 - To provide a stable and a low-noise power-supply (1.5V) for the VCO
- Problem: Power-supply noise reduction performance of the LDO is inadequate
 - Improved PLL Jitter performance when the LDO is disabled
- LDO cannot be tested directly (no access to LDO output, a sensitive node for noise injection)
 - PLL output signal is modulated by the output noise of the LDO
- Note: LDO is not a part of the PLL Core blocks (PFD, CP, LPF, VCO and divider)



TIE histogram of the CLKPLL – LDO ENABLED



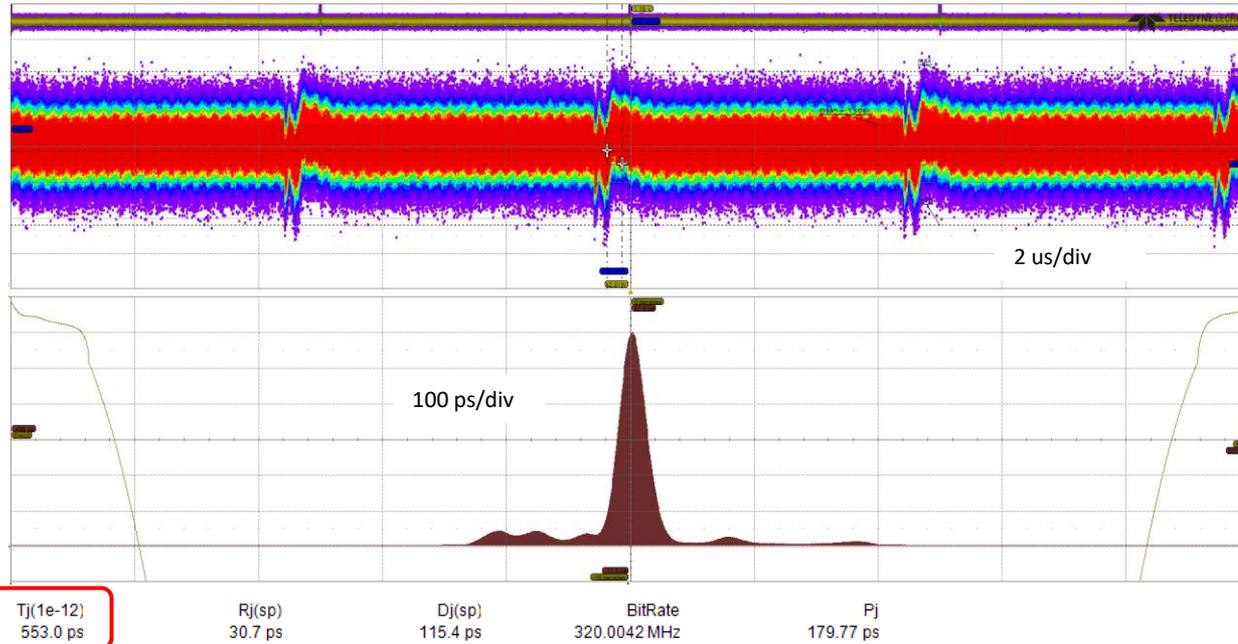
Eye diagram serializer DATA[0] LVDS buffer output, Data Pattern: ([0xAAAA] x 16), Clock period: 3.125 ns (320 MHz), LDO ENABLED



ISSUE 2: NOISE INJECTION FROM DIGITAL POWER SUPPLY TO THE PLL BLOCK

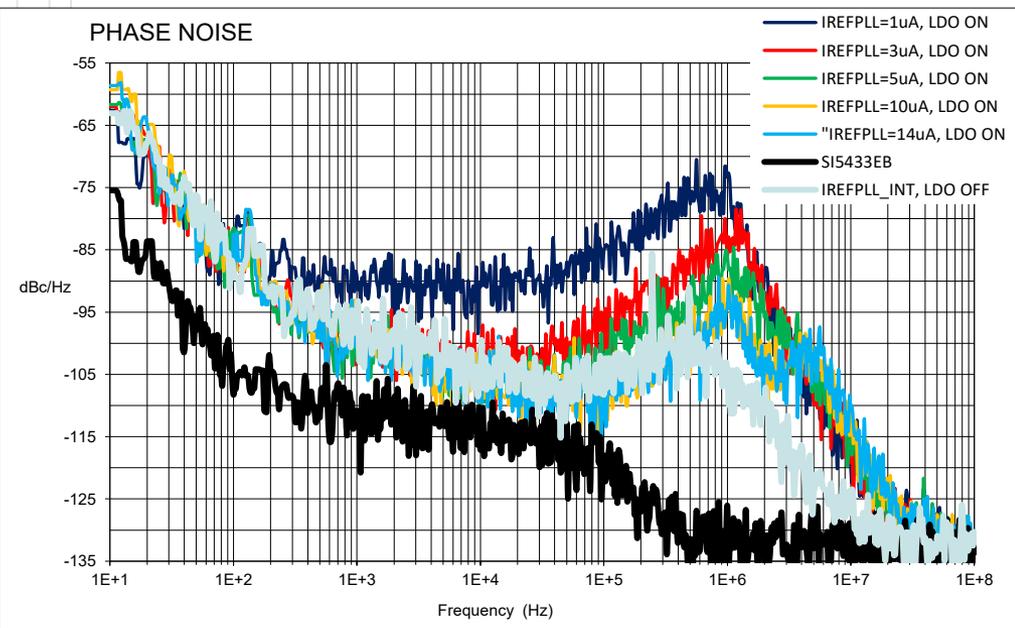
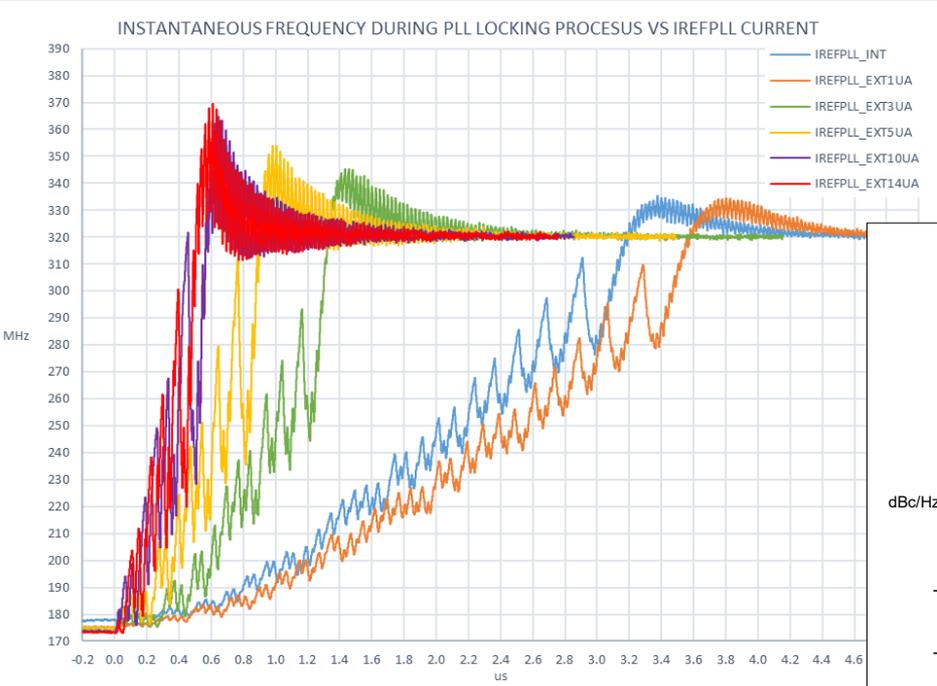
- To disable the LDO is not a solution (Note: using the internal reference current IREFPLL)
 - Good PLL jitter performance at very low activity level of the sensor
 - Problem: Activity of the sequencer block results in noise injection from the digital power supply to the PLL block

TIE histogram of the CLKPLL and instantaneous clock frequency-tracking plot in persistence mode – SEQUENCER BLOCK RUNNING



TEMPORARY SOLUTION FOR THE ISSUE OF LDO: EXTERNAL REFERENCE CURRENT (IREFPLL)

- LDO enabled and use of external reference current (IREFPLL) with the higher current (1uA -> 10...14uA)
- Problem: LDO and PLL shares the common reference current circuitry (IREFPLL)
- Increase of the reference current results in:
 - PLL loop bandwidth increase (more reactive, stability?), the PLL is more sensible for the reference clock jitter
 - LDO has improved power-supply noise reduction performance ($TJ_{pk-pk}(BER = 10^{-12})$: 1500 ps -> 310 ps)



CONCLUSION

- The PLL Core is operational in low power supply noise conditions (Sequencer block/data readout not started)
- Jitter performance issue of the PLL is related to the LDO block, not to the PLL Core blocks
- Power-supply noise reduction performance of the LDO is inadequate
- In normal operation conditions of MIMOSIS-2.1 , the LDO is required to obtain adequate PLL jitter performance
- Temporary solutions for the LDO issue: use of an external PLL reference current (IREFPLL)